

Normally – OFF Silicon Carbide Junction Transistor

V_{DS}	=	600 V
$R_{DS(ON)}$	=	65 mΩ
I_D ($T_C = 25^\circ\text{C}$)	=	32 A
h_{FE} ($T_C = 25^\circ\text{C}$)	=	110

Features

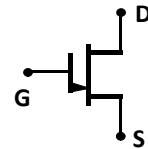
- 225°C maximum operating temperature
- Electrically Isolated Base Plate
- Gate Oxide Free SiC Switch
- Exceptional Safe Operating Area
- Excellent Gain Linearity
- Temperature Independent Switching Performance
- Low Output Capacitance
- Positive Temperature Coefficient of $R_{DS,ON}$
- Suitable for Connecting an Anti-parallel Diode

Advantages

- Compatible with Si MOSFET/IGBT Gate Drive ICs
- > 20 μs Short-Circuit Withstand Capability
- Lowest-in-class Conduction Losses
- High Circuit Efficiency
- Minimal Input Signal Distortion
- High Amplifier Bandwidth

Package

- RoHS Compliant



TO – 257 (Isolated Base-plate Hermetic Package)

Applications

- Down Hole Oil Drilling, Geothermal Instrumentation
- Hybrid Electric Vehicles (HEV)
- Solar Inverters
- Switched-Mode Power Supply (SMPS)
- Power Factor Correction (PFC)
- Induction Heating
- Uninterruptible Power Supply (UPS)
- Motor Drives

Absolute Maximum Ratings

Parameter	Symbol	Conditions	Values	Unit
Drain – Source Voltage	V_{DS}	$V_{GS} = 0\text{ V}$	600	V
Continuous Drain Current	I_D	$T_J = 225^\circ\text{C}, T_C = 25^\circ\text{C}$	32	A
Gate Peak Current	I_{GM}		2	A
Turn-Off Safe Operating Area	RBSOA	$T_{VJ} = 225^\circ\text{C}, I_G = 1.5\text{ A},$ Clamped Inductive Load	$I_{D,max} = 32$ @ $V_{DS} \leq V_{DSmax}$	A
Short Circuit Safe Operating Area	SCSOA	$T_{VJ} = 225^\circ\text{C}, I_G = 1.5\text{ A}, V_{DS} = 400\text{ V},$ Non Repetitive	>20	μs
Reverse Gate – Source Voltage	V_{GS}		30	V
Reverse Drain – Source Voltage	V_{DS}		40	V
Power Dissipation	P_{tot}	$T_J = 225^\circ\text{C}, T_C = 25^\circ\text{C}$	172	W
Operating and Storage Temperature	T_J, T_{stg}		-55 to 225	$^\circ\text{C}$

Electrical Characteristics

Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
On Characteristics						
Drain – Source On Resistance	$R_{DS(ON)}$	$I_D = 20\text{ A}, I_G = 400\text{ mA}, T_J = 25^\circ\text{C}$		65		mΩ
		$I_D = 20\text{ A}, I_G = 500\text{ mA}, T_J = 125^\circ\text{C}$		90		
		$I_D = 20\text{ A}, I_G = 1000\text{ mA}, T_J = 175^\circ\text{C}$		110		
		$I_D = 20\text{ A}, I_G = 1000\text{ mA}, T_J = 250^\circ\text{C}$		165		
Gate Forward Voltage	$V_{GS(FWD)}$	$I_G = 1000\text{ mA}, T_J = 25^\circ\text{C}$		3.0		V
		$I_G = 1000\text{ mA}, T_J = 250^\circ\text{C}$		2.7		
DC Current Gain	h_{FE}	$V_{DS} = 5\text{ V}, I_D = 20\text{ A}, T_J = 25^\circ\text{C}$		112		
		$V_{DS} = 5\text{ V}, I_D = 20\text{ A}, T_J = 125^\circ\text{C}$		78		
		$V_{DS} = 5\text{ V}, I_D = 20\text{ A}, T_J = 175^\circ\text{C}$		73		
		$V_{DS} = 5\text{ V}, I_D = 20\text{ A}, T_J = 250^\circ\text{C}$		69		
Off Characteristics						
Drain Leakage Current	I_{DSS}	$V_R = 600\text{ V}, V_{GS} = 0\text{ V}, T_J = 25^\circ\text{C}$		10		μA
		$V_R = 600\text{ V}, V_{GS} = 0\text{ V}, T_J = 175^\circ\text{C}$		50		
		$V_R = 600\text{ V}, V_{GS} = 0\text{ V}, T_J = 250^\circ\text{C}$		100		
Gate Leakage Current	I_{SG}	$V_{SG} = 20\text{ V}, T_J = 25^\circ\text{C}$		20		nA

Electrical Characteristics

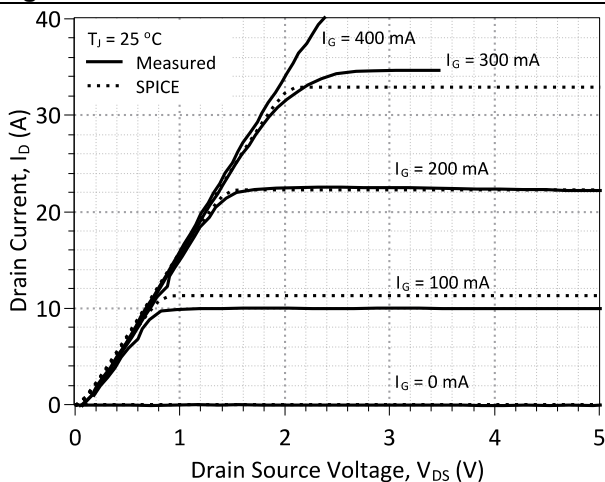
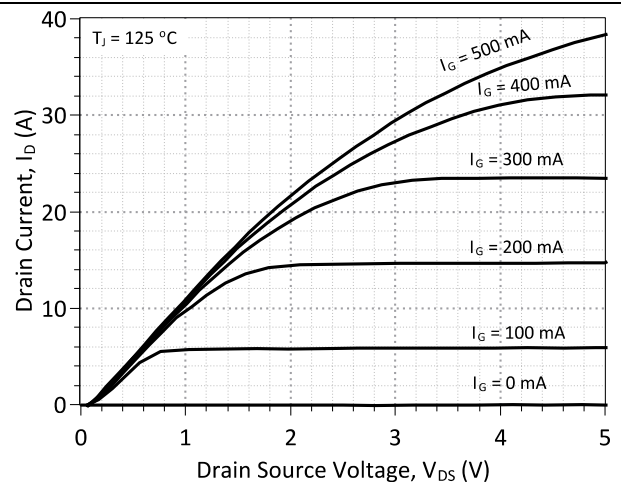
Parameter	Symbol	Conditions	Values			Unit
			min.	typ.	max.	
Capacitance Characteristics						
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{ V}, V_D = 100\text{ V}, f = 1\text{ MHz}$		2500		pF
Reverse Transfer/Output Capacitance	C_{RSS}/C_{OSS}	$V_D = 100\text{ V}, f = 1\text{ MHz}$		158		pF
Output Capacitance Stored Energy	E_{OSS}	$V_{GS} = 0\text{ V}, V_D = 100\text{ V}, f = 1\text{ MHz}$		0.8		μJ

Switching Characteristics

Gate Resistance, Internal	$R_{G(INT)}$	$f = 1\text{ MHz}, V_{AC} = 25\text{ mV}, T_J = 225\text{ }^\circ\text{C}$		2.6		Ω		
Turn On Delay Time	$t_{d(on)}$	$T_J = 25\text{ }^\circ\text{C}, V_{DS} = 400\text{ V}, I_D = 20\text{ A},$ Two-Level Gate Drive, $R_G = 1.53\ \Omega, C_G = 25\text{ nF},$ $V_{GH} = 18\text{ V}, V_{GL} = 6\text{ V}, V_{EE} = -10\text{ V},$ IXDD614 Gate Drive IC, $L = 287\ \mu\text{H}, \text{FWD} = \text{GB20SLT12},$ Refer to Fig. 15 for gate current waveform		90		ns		
Rise Time	t_r			40		ns		
Turn Off Delay Time	$t_{d(off)}$			50		ns		
Fall Time	t_f			30		ns		
Turn-On Energy Per Pulse	E_{on}				810		μJ	
Turn-Off Energy Per Pulse	E_{off}				95		μJ	
Total Switching Energy	E_{ts}				905		μJ	
Turn On Delay Time	$t_{d(on)}$		$T_J = 250\text{ }^\circ\text{C}, V_{DS} = 400\text{ V}, I_D = 20\text{ A},$ Two-Level Gate Drive, $R_G = 1.53\ \Omega, C_G = 25\text{ nF},$ $V_{GH} = 18\text{ V}, V_{GL} = 6\text{ V}, V_{EE} = -10\text{ V},$ IXDD614 Gate Drive IC, $L = 287\ \mu\text{H}, \text{FWD} = \text{GB20SLT12},$ Refer to Fig. 15 for gate current waveform		90		ns	
Rise Time	t_r				20		ns	
Turn Off Delay Time	$t_{d(off)}$				50		ns	
Fall Time	t_f				20		ns	
Turn-On Energy Per Pulse	E_{on}					140		μJ
Turn-Off Energy Per Pulse	E_{off}					45		μJ
Total Switching Energy	E_{ts}				185		μJ	

Thermal Characteristics

Thermal resistance, junction - case	R_{thJC}	1.16	$^\circ\text{C/W}$
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Figures

Figure 1: Typical Output Characteristics at 25 °C

Figure 2: Typical Output Characteristics at 125 °C

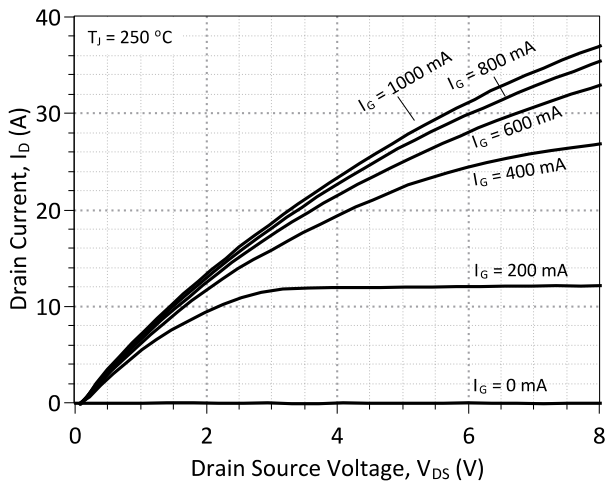


Figure 3: Typical Output Characteristics at 250 °C

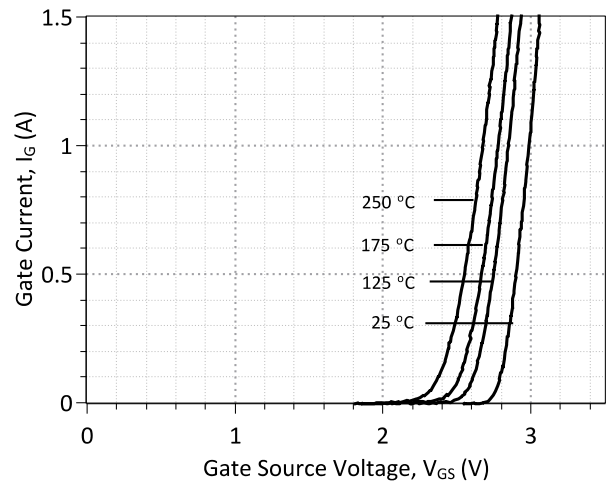


Figure 4: Typical Gate Source I-V Characteristics vs. Temperature

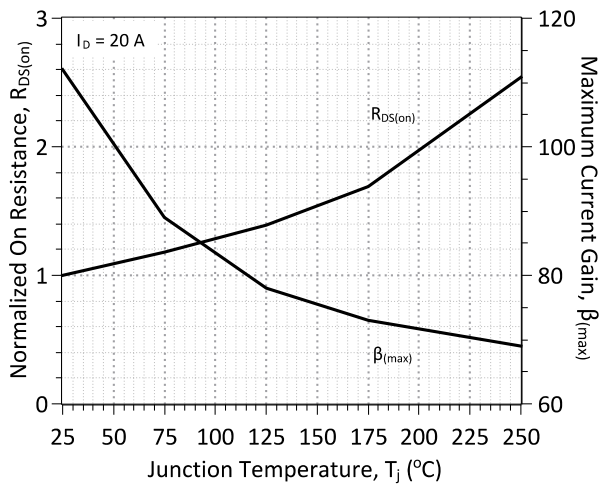


Figure 5: Normalized On-Resistance and Current Gain vs. Temperature

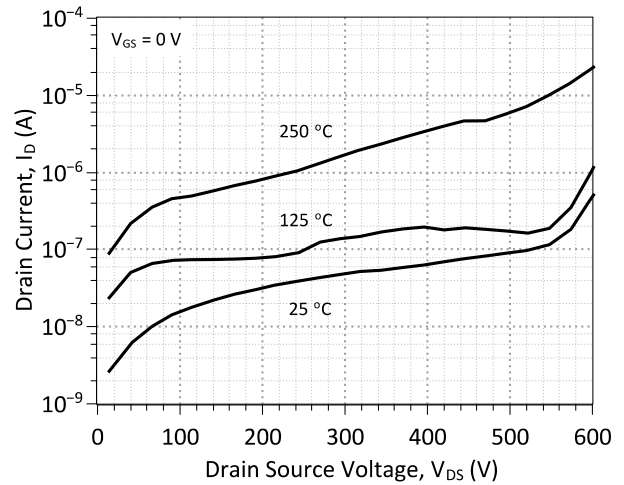


Figure 6: Typical Blocking Characteristics

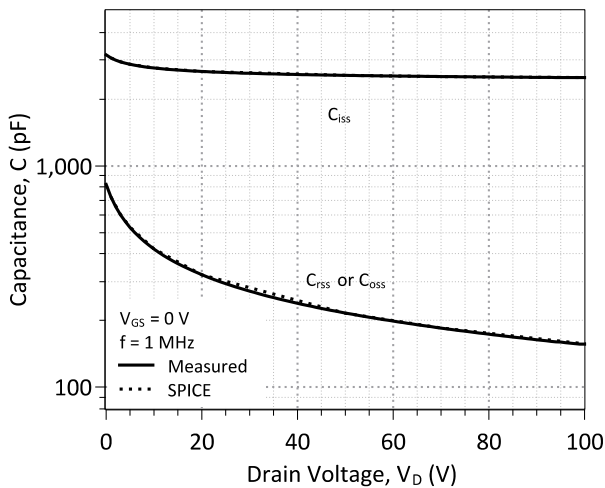


Figure 7: Capacitance Characteristics

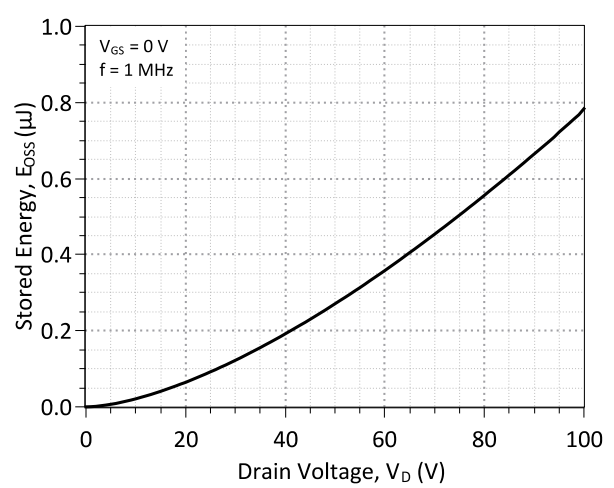


Figure 8: Output Capacitance Stored Energy

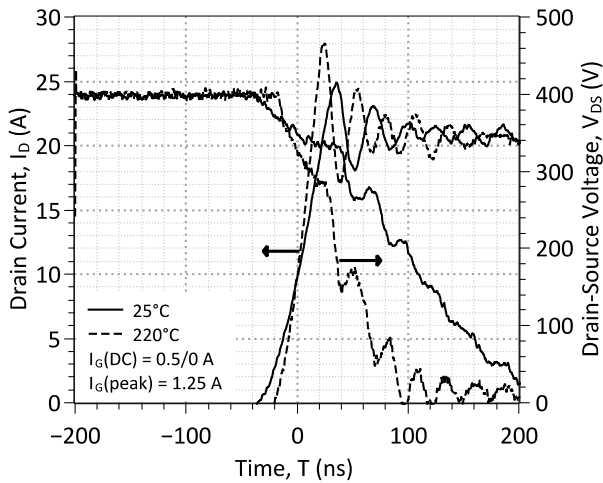


Figure 9: Typical Hard-switched Turn On Waveforms

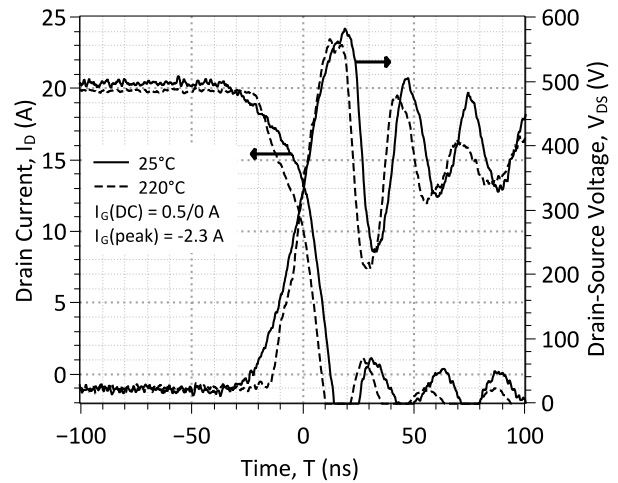


Figure 10: Typical Hard-switched Turn Off Waveforms

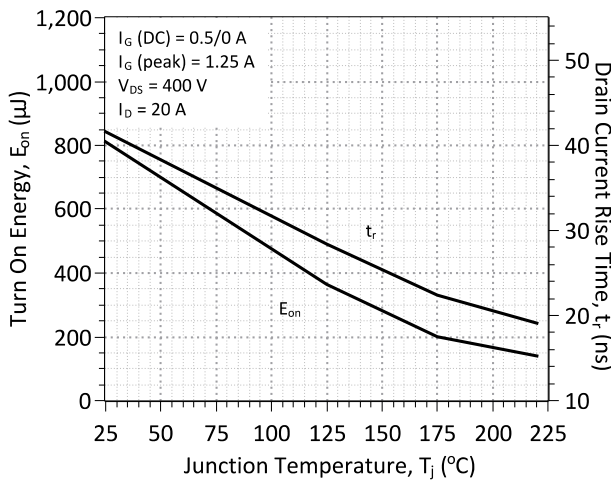


Figure 11: Typical Turn On Energy Losses and Switching Times vs. Temperature

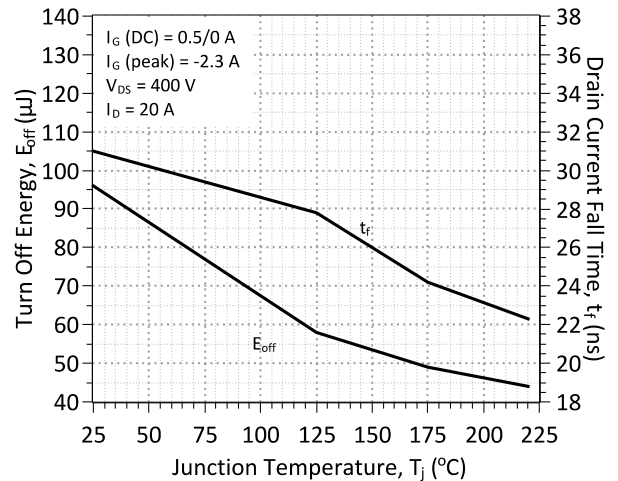


Figure 12: Typical Turn Off Energy Losses and Switching Times vs. Temperature

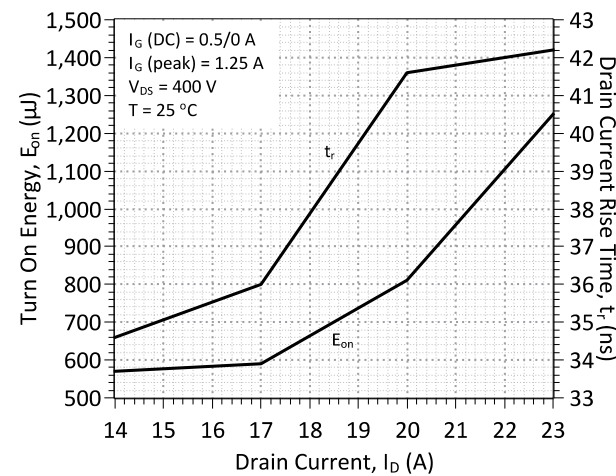


Figure 13: Typical Turn On Energy Losses and Switching Times vs. Drain Current

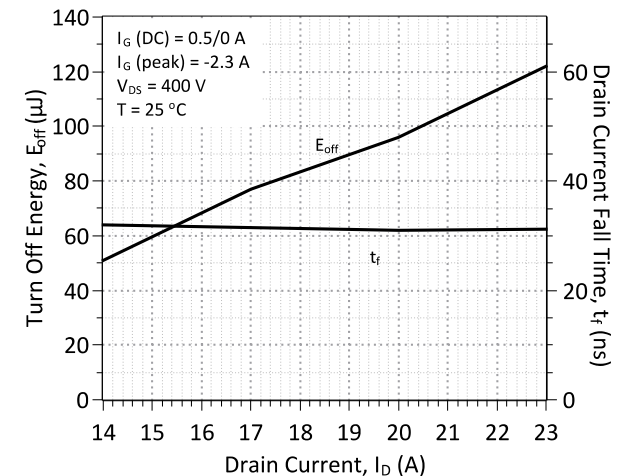


Figure 14: Typical Turn Off Energy Losses and Switching Times vs. Drain Current

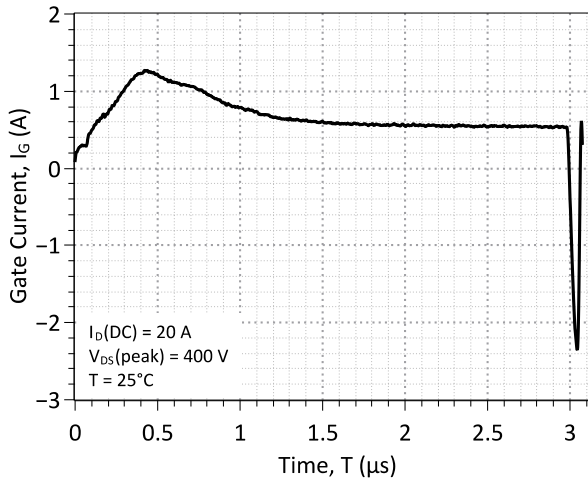


Figure 15: Typical Gate Current Waveform

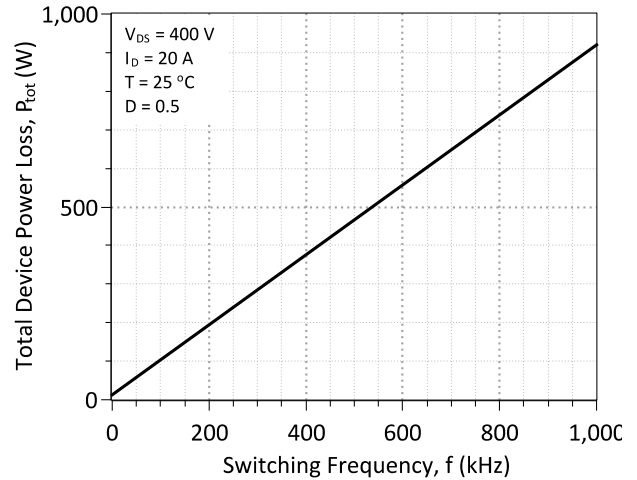


Figure 16: Typical Hard Switched Device Power Loss vs. Switching Frequency¹

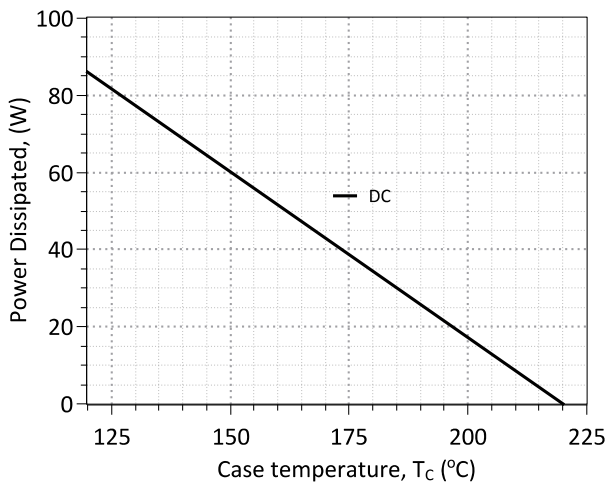


Figure 17: Power Derating Curve

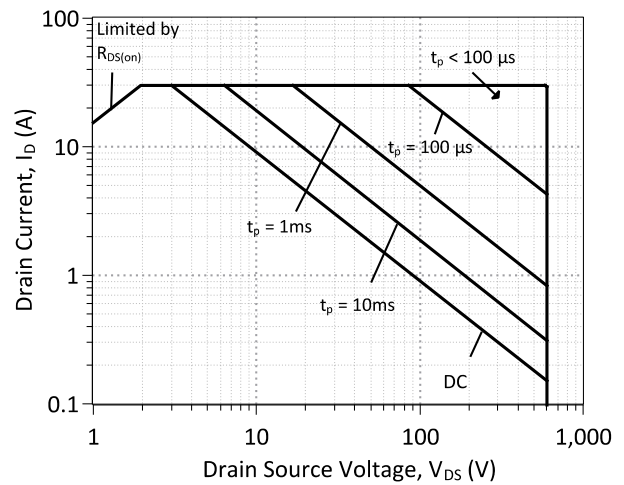


Figure 18: Forward Bias Safe Operating Area at $T_c=120^\circ\text{C}$

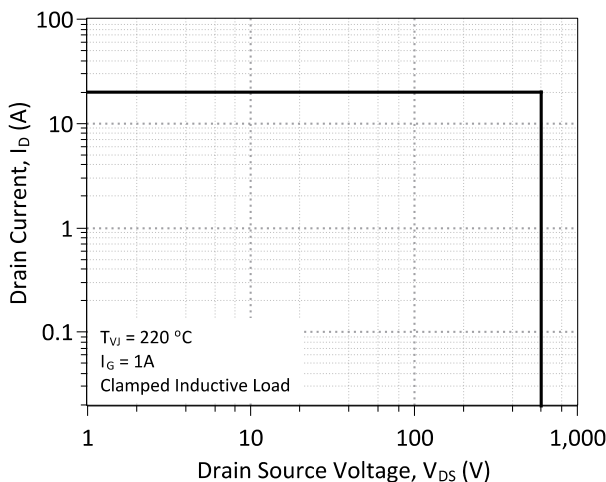


Figure 19: Turn-Off Safe Operating Area

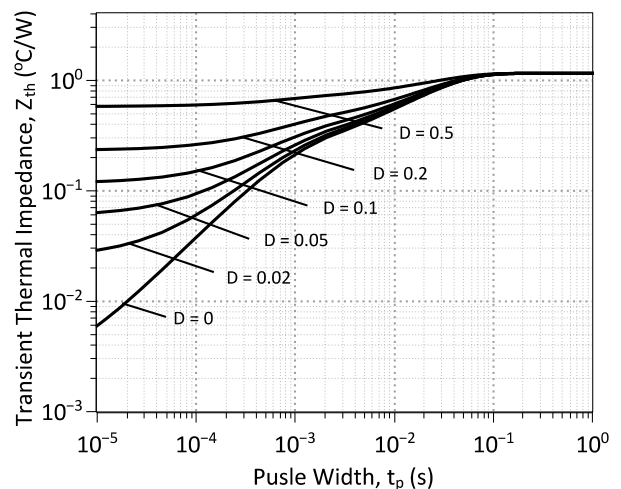


Figure 20: Transient Thermal Impedance

¹ – Representative values based on device switching energy loss. Actual losses will depend on gate drive conditions, device load, and circuit topology.

Gate Drive Theory of Operation

The SJT transistor is a current controlled transistor which requires a positive gate current for turn-on as well as to remain in on-state. An ideal gate current waveform for ultra-fast switching of the SJT, while maintaining low gate drive losses, is shown in Figure 21.

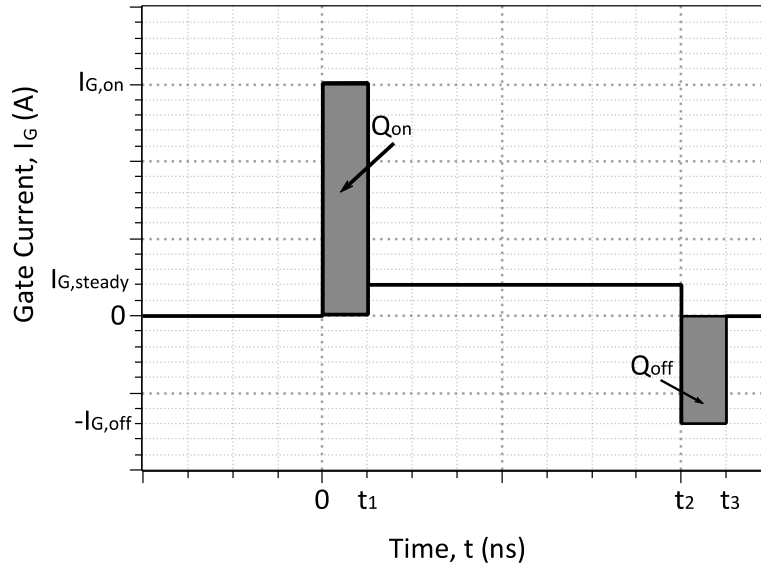


Figure 21: Idealized Gate Current Waveform

Gate Currents, $I_{G,pk}/-I_{G,pk}$ and Voltages during Turn-On and Turn-Off

An SJT is rapidly switched from its blocking state to on-state, when the necessary gate charge, Q_G , for turn-on is supplied by a burst of high gate current, $I_{G,on}$, until the gate-source capacitance, C_{GS} , and gate-drain capacitance, C_{GD} , are fully charged.

$$I_{G,on} * t_1 \geq Q_{gs} + Q_{gd}$$

The $I_{G,on}$ pulse should ideally terminate, when the drain voltage falls to its on-state value, in order to avoid unnecessary drive losses during the steady on-state. In practice, the rise time of the $I_{G,on}$ pulse is affected by the parasitic inductances, L_{par} in the package and drive circuit. A voltage developed across the parasitic inductance in the source path, L_s , can de-bias the gate-source junction, when high drain currents begin to flow through the device. The applied gate voltage should be maintained high enough, above the $V_{GS,ON}$ level to counter these effects.

A high negative peak current, $-I_{G,off}$ is recommended at the start of the turn-off transition, in order to rapidly sweep out the injected carriers from the gate, and achieve rapid turn-off. While satisfactory turn off can be achieved with $V_{GS} = 0 V$, a negative gate voltage V_{GS} may be used in order to speed up the turn-off transition.

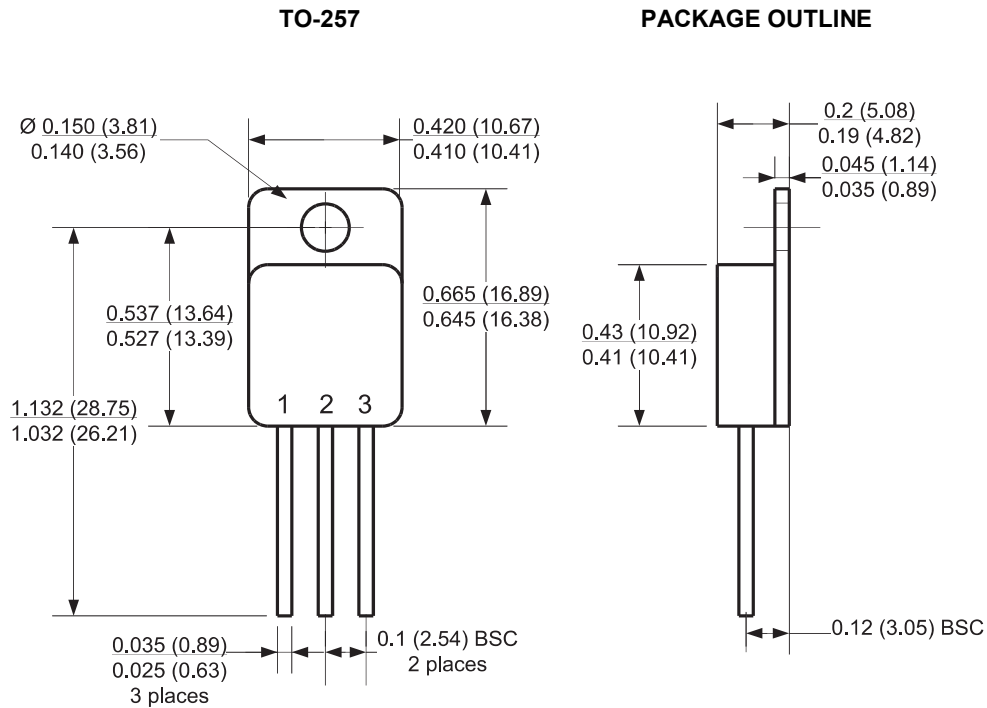
Steady On-State

After the device is turned on, I_G may be advantageously lowered to $I_{G,steady}$ for reducing unnecessary gate drive losses. The $I_{G,steady}$ is determined by noting the DC current gain, h_{FE} , of the device.

The desired $I_{G,steady}$ is determined by the peak device junction temperature T_J during operation, drain current I_D , DC current gain h_{FE} , and a 50 % safety margin to ensure operating the device in the saturation region with low on-state voltage drop by the equation:

$$I_{G,steady} \approx \frac{I_D}{h_{FE}(T, I_D)} * 1.5$$

Package Dimensions:



NOTE
 1. CONTROLLED DIMENSION IS INCH. DIMENSION IN BRACKET IS MILLIMETER.
 2. DIMENSIONS DO NOT INCLUDE END FLASH, MOLD FLASH, MATERIAL PROTRUSIONS

Revision History			
Date	Revision	Comments	Supersedes
2014/08/25	6	Updated Electrical Characteristics	
2014/03/18	5	Updated Gate Drive Section	
2014/02/10	4	Updated Electrical Characteristics	
2013/12/19	3	Updated Gate Drive Section	
2013/12/09	2	Updated Electrical Characteristics	
2013/11/18	1	Updated Electrical Characteristics	
2012/08/24	0	Initial release	

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SPICE Model Parameters

This is a secure document. Please copy this code from the SPICE model PDF file on our website (http://www.genesicsemi.com/images/hit_sic/sjt/2N7639-GA_SPICE.pdf) into LTSPICE (version 4) software for simulation of the 2N7639-GA.

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*      MODEL OF GeneSiC Semiconductor Inc.
*
*      $Revision:   1.2           $
*      $Date:      23-JUN-2014   $
*
*      GeneSiC Semiconductor Inc.
*      43670 Trade Center Place Ste. 155
*      Dulles, VA 20166
*
*      COPYRIGHT (C) 2014 GeneSiC Semiconductor Inc.
*      ALL RIGHTS RESERVED
*
* These models are provided "AS IS, WHERE IS, AND WITH NO WARRANTY
* OF ANY KIND EITHER EXPRESSED OR IMPLIED, INCLUDING BUT NOT LIMITED
* TO ANY IMPLIED WARRANTIES OF MERCHANTABILITY AND FITNESS FOR A
* PARTICULAR PURPOSE."
* Models accurate up to 2 times rated drain current.
*
.model 2N7639-GA NPN
+ IS      5.00E-47
+ ISE     1.26E-28
+ EG      3.23
+ BF      114
+ BR      0.55
+ IKF     700
+ NF      1
+ NE      2
+ RB      2.60
+ RE      0.01
+ RC      0.045
+ CJC     8.2281E-10
+ VJC     3.31126
+ MJC     0.48117
+ CJE     2.33957E-9
+ VJE     2.91486
+ MJE     0.48211
+ XTI     3
+ XTB     -1.2
+ TRC1    6.20E-03
+ VCEO    600
+ ICRATING 32
+ MFG     GeneSiC_Semiconductor
*
* End of 2N7639-GA SPICE Model
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